

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunji MAEDA et al.

Serial No. : Unassigned (§53(b) Cont. of 10/098,478 filed 18 March 2002)

Filed : 17 October 2003

For : MANUFACTURING METHOD OF SEMICONDUCTOR SUBSTRATE AND METHOD AND APPARATUS FOR INSPECTING DEFECTS OF PATTERNS OF AN OBJECT TO BE INSPECTED

Art Unit : Unassigned (Parent - 2877)

Examiner : Unassigned (Parent - Hoa Q. Pham)

Conf. No : Unassigned (Parent - 5054)

PRELIMINARY AMENDMENT

Mail Stop Patent Application
Commissioner for Patents
POB 1450
Alexandria, Virginia 22313-1450

17 October 2003

Sir:

Prior to calculating the filing fee for the above-identified application, the following amendments and remarks are respectfully submitted.

In accordance with the revised format of the manner of making amendments under 37 CFR §1.121 as set forth in the Final Rule effective 30 July 2003, each section of amendment herein begins on a new page, and changes are shown by strike-through (or double brackets where appropriate) and underlining to indicate deletions and additions, respectively. A complete listing of all claims ever presented in the application is given with the current status of each claim, and only the text of all pending and withdrawn claims is presented in full, with those not being amended herein being presented in clean version.